

Features

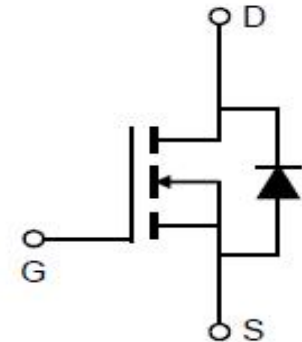
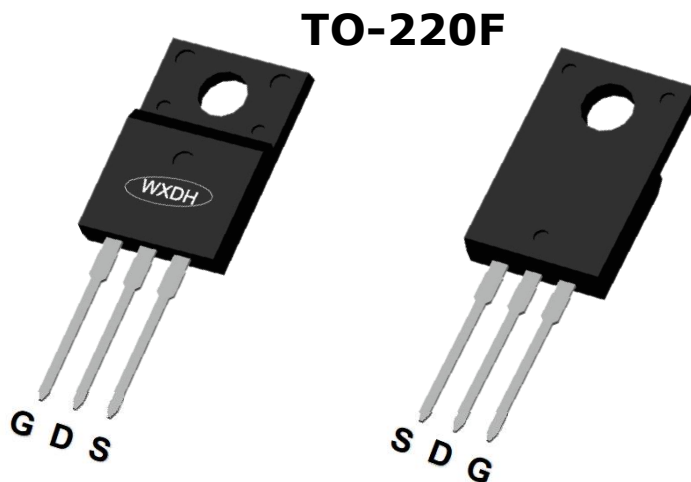
- Low on resistance
- Low reverse transfer capacitances
- 100% single pulse avalanche energy test
- 100% ΔVDS test
- Pb-Free plating / Halogen-Free / RoHS compliant

Applications

- Power switching applications
- DC-DC converters
- Full bridge control

Key Parameters

| | |
|------------------|--------|
| V_{DS} | 150V |
| $R_{DS(on)typ.}$ | 9.5mΩ |
| I_D | 52A |
| V_{TH} | 3V |
| $C_{iss@10V}$ | 3863pF |
| Q_{gd} | 5nC |



Marking & Packing Information

| Part # | Package | Marking | Tube/Reel | Qty(pcs) |
|------------|---------|------------|-----------|----------|
| DHS110N15F | TO-220F | DHS110N15F | Tube | 1000/box |

Absolute Maximum Ratings

| Parameter | Symbol | Value | Unit |
|---|----------------|------------|------------------|
| Drain-source voltage | V_{DS} | 150 | V |
| Gate-Source voltage | V_{GS} | ±20 | V |
| Continuous drain current $T_C = 25^\circ\text{C}$ $T_C = 100^\circ\text{C}$ | I_D | 52 37 | A |
| Pulsed drain current ($T_C = 25^\circ\text{C}$, t_p limited by T_{jmax}) | $I_{D\ pulse}$ | 207 | A |
| Avalanche energy, single pulse ($L=0.5\text{mH}$, $R_g=25\Omega$) | E_{AS} | 600 | mJ |
| Power dissipation ($T_C = 25^\circ\text{C}$) | P_{tot} | 54 | W |
| Operating junction and storage temperature | T_j, T_{stg} | -55...+175 | $^\circ\text{C}$ |

Thermal Resistance

| Parameter | Symbol | Max | Unit |
|--|------------|-----|--------------------|
| Thermal resistance, junction – case. | R_{thJC} | 2.8 | $^\circ\text{C/W}$ |
| Thermal resistance, junction – ambient(min. footprint) | R_{thJA} | 55 | |

Electrical Characteristic (at $T_j = 25^\circ\text{C}$, unless otherwise specified)

Static Characteristic

| Parameter | Symbol | Value | | | Unit | Test Condition |
|----------------------------------|--------------|-------|------|----------|---------------|---|
| | | min. | typ. | max. | | |
| Drain-source breakdown voltage | BV_{DSS} | 150 | - | - | V | $V_{GS}=0V, I_D=250\mu\text{A}$ |
| Gate threshold voltage | $V_{GS(th)}$ | 2.0 | 3.0 | 4.0 | V | $V_{DS}=V_{GS}, I_D=250\mu\text{A}$ |
| Zero gate voltage drain current | I_{DSS} | - | - | 1 100 | μA | $V_{DS}=150V, V_{GS}=0V$ $T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$ |
| Gate-source leakage current | I_{GSS} | - | - | 100 | nA | $V_{GS}=20V, V_{DS}=0V$ |
| Drain-source on-state resistance | $R_{DS(on)}$ | | 9.5 | 11.5 | mΩ | $V_{GS}=10V, I_D=20A,$ $T_j=25^\circ\text{C}$ |

Dynamic Characteristic

| Parameter | Symbol | Value | | | Unit | Test Condition |
|------------------------------|--------------|-------|------|------|----------|--|
| | | min. | typ. | max. | | |
| Input Capacitance | C_{iss} | - | 3863 | - | pF | $V_{GS}=0V, V_{DS}=75V,$ $f=1MHz$ |
| Output Capacitance | C_{oss} | - | 295 | - | | |
| Reverse Transfer Capacitance | C_{rss} | - | 11.4 | - | | |
| Gate Total Charge | Q_G | - | 47 | - | nC | $V_{GS}=10V, V_{DS}=75V,$ $I_D=20A, f=1MHz$ |
| Gate-Source charge | Q_{gs} | - | 19 | - | | |
| Gate-Drain charge | Q_{gd} | - | 5 | - | | |
| Turn-on delay time | $t_{d(on)}$ | - | 15 | - | ns | $V_{GS}=10V, V_{DD}=75V,$ $I_D=20A, R_{G_ext}=3\Omega$ |
| Rise time | t_r | - | 29 | - | | |
| Turn-off delay time | $t_{d(off)}$ | - | 34 | - | | |
| Fall time | t_f | - | 11 | - | | |
| Gate resistance | R_G | - | 2.5 | - | Ω | $V_{GS}=0V, V_{DS}=0V,$ $f=1MHz$ |

Body Diode Characteristic

| Parameter | Symbol | Value | | | Unit | Test Condition |
|-------------------------------|----------|-------|------|------|------|----------------------------------|
| | | min. | typ. | max. | | |
| Diode Max Current | I_S | | - | 52 | A | - |
| Diode Forward Voltage | V_{SD} | - | - | 1.2 | V | $V_{GS}=0V, I_{SD}=20A$ |
| Diode Reverse Recovery Time | t_{rr} | - | 93 | - | ns | $I_F=20A,$ $dI/dt=100A/\mu s$ |
| Diode Reverse Recovery Charge | Q_{rr} | - | 292 | - | nC | |

Typical Characteristics Diagram

Fig1. Output Characteristics

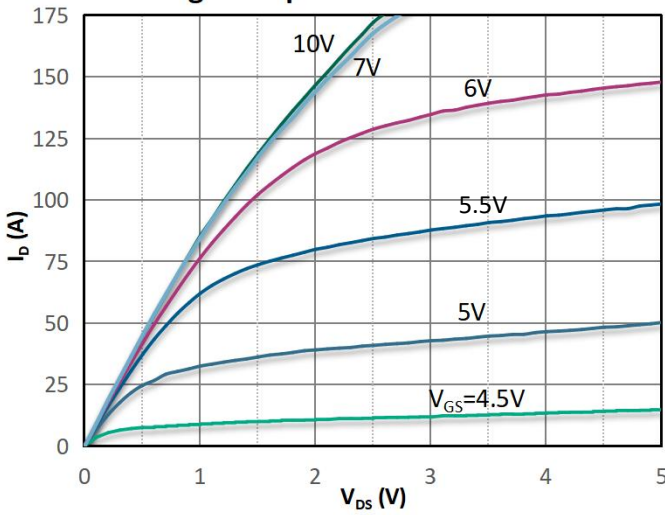


Fig2. Transfer Characteristics

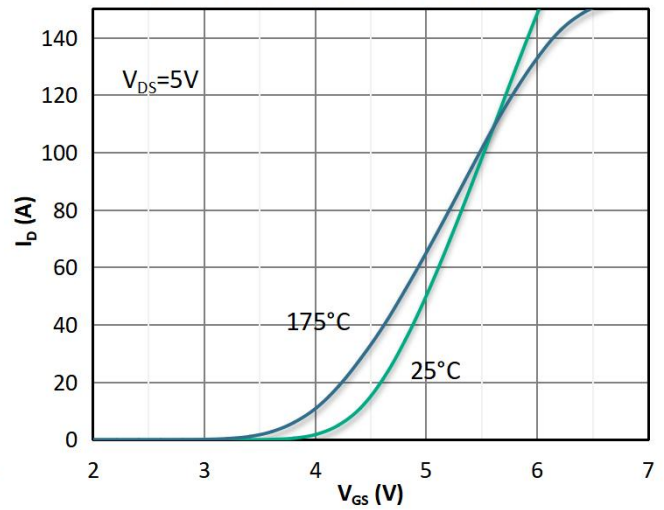


Fig3. Rds(on) vs Drain Current

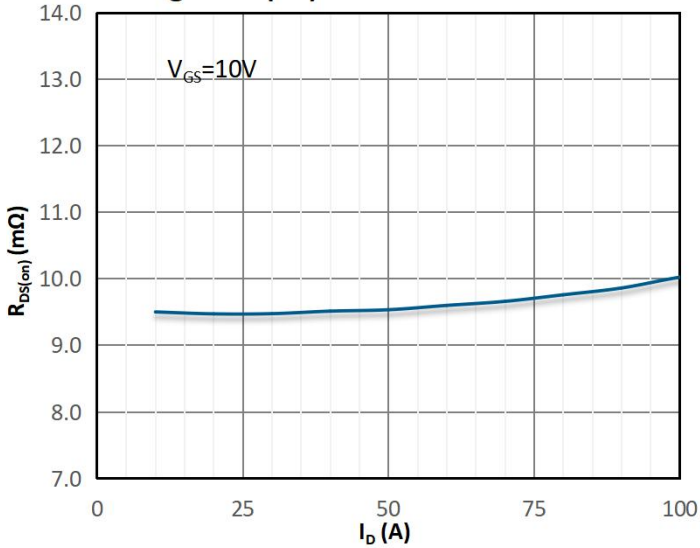


Fig 4. Rds(on) vs Gate Voltage

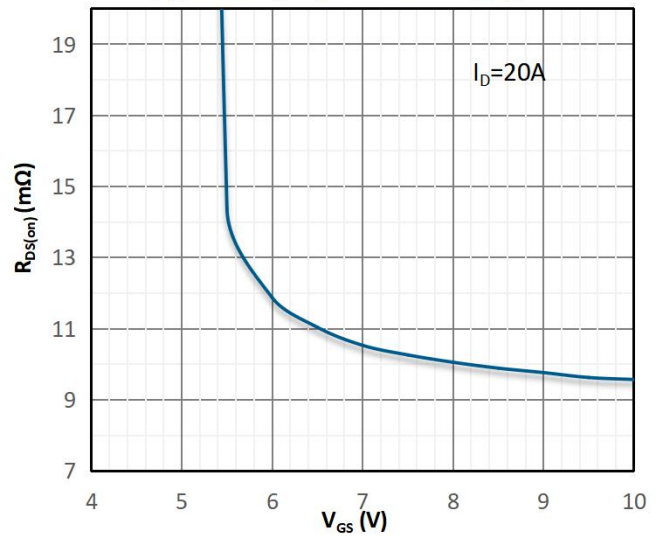


Fig5. Rds(on) vs. Temperature

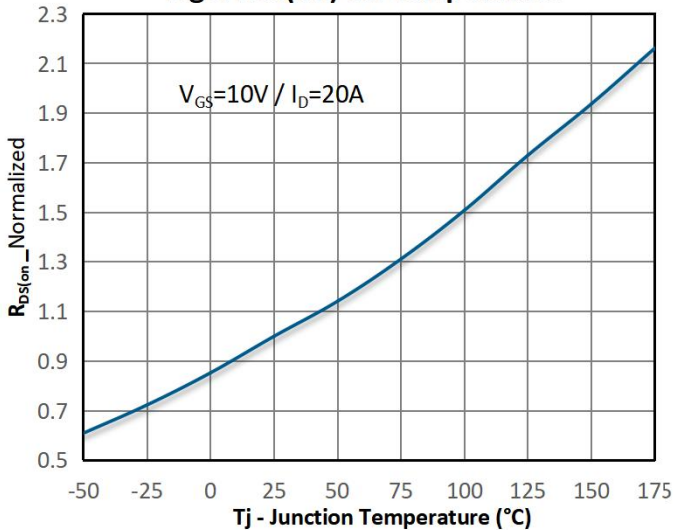
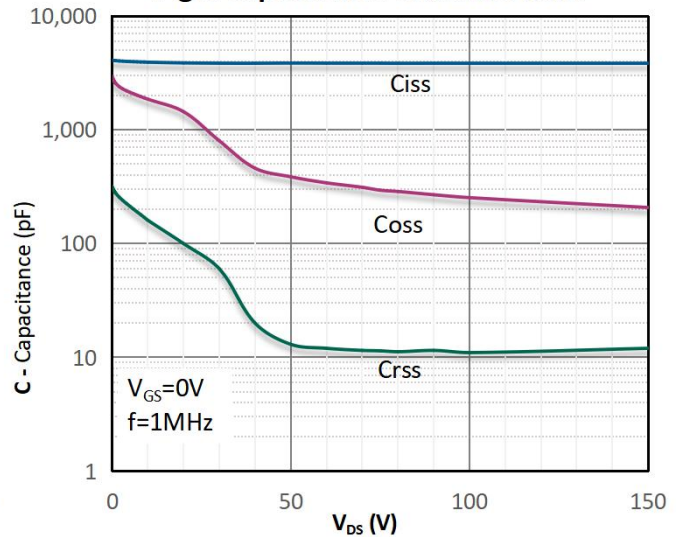


Fig6. Capacitance Characteristics



Typical Characteristics Diagram

Fig7. Gate Charge Characteristics

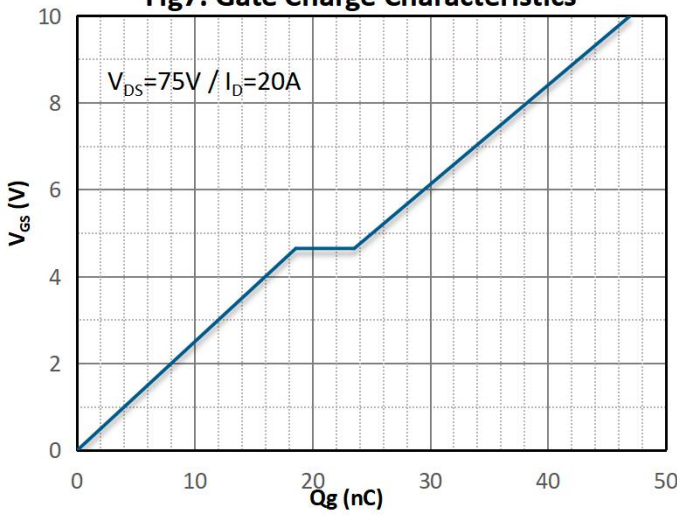


Fig8. Body-diode Forward Characteristics

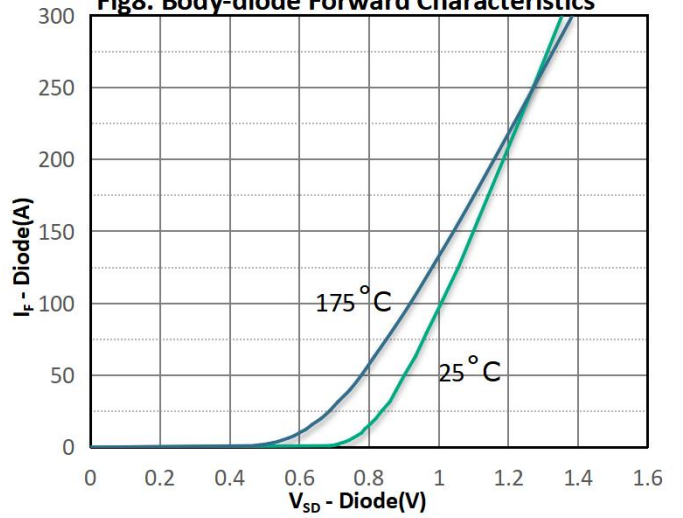


Fig9. Power De-rating

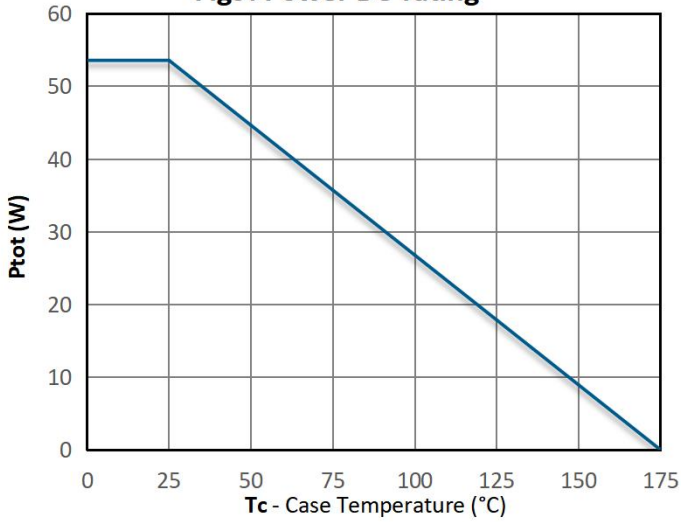


Fig10. Current De-rating

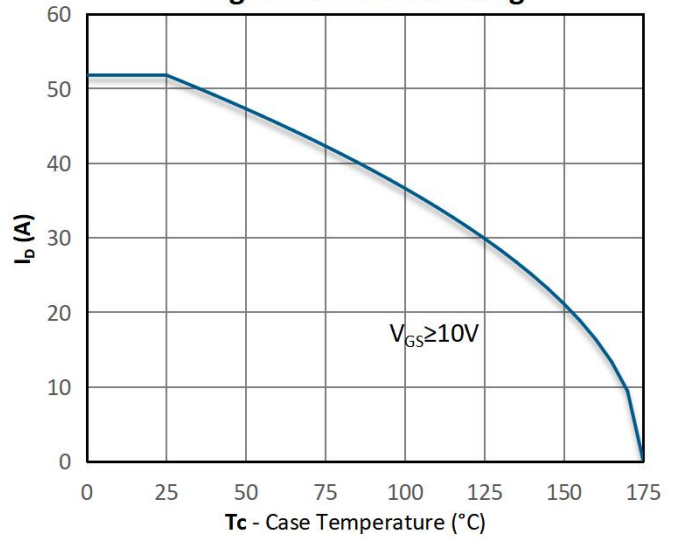


Fig11. Safe Operating Area

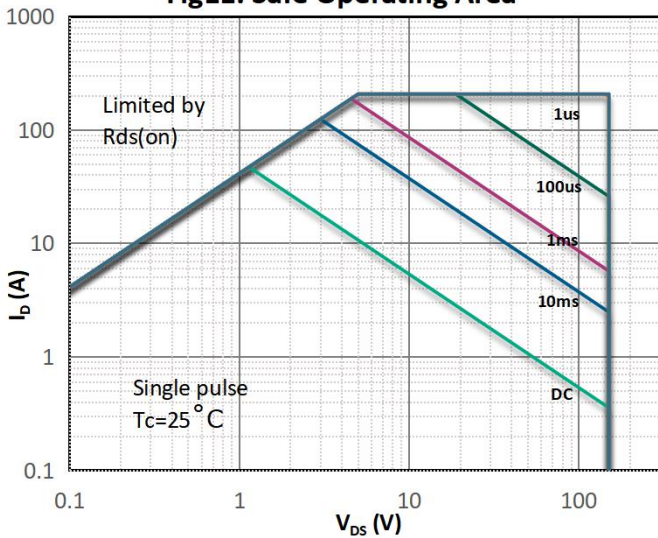
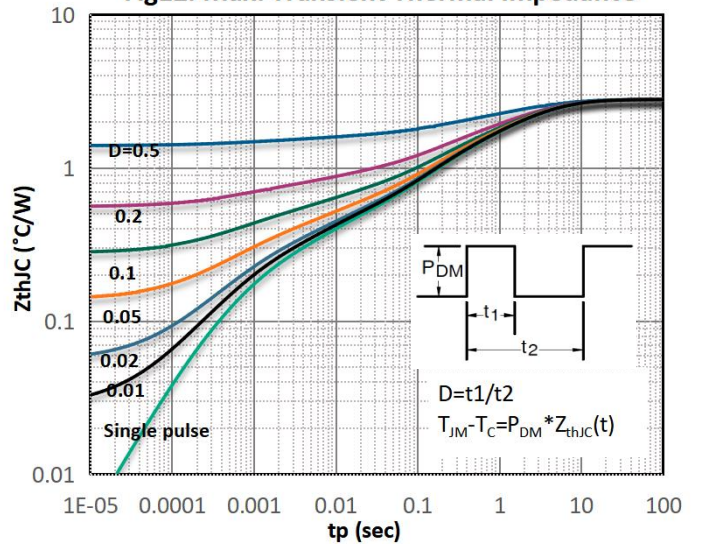
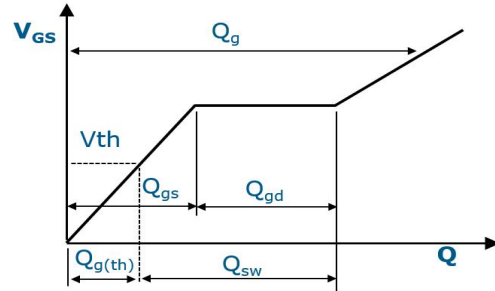
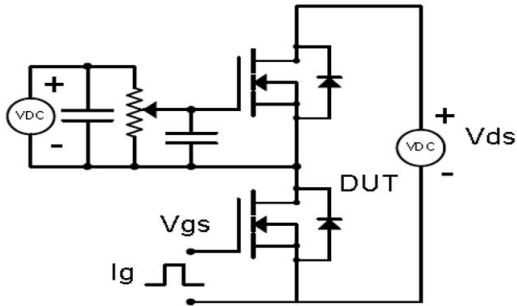


Fig12. Max. Transient Thermal Impedance

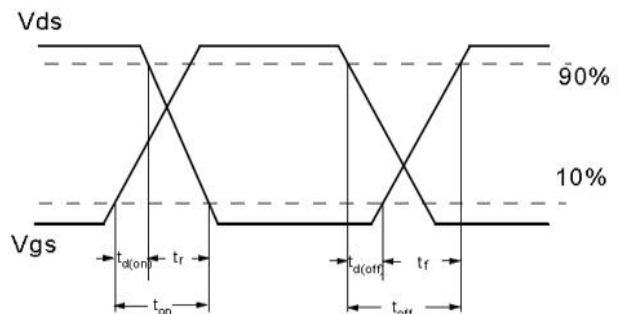
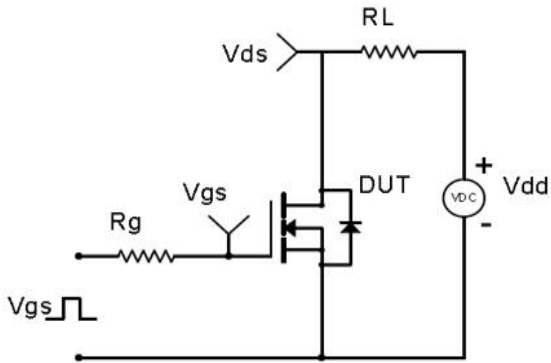


Test Circuit & Waveform

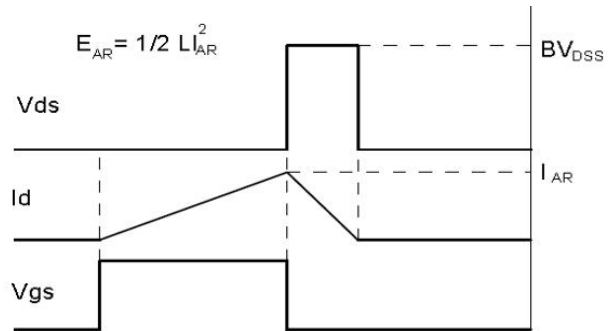
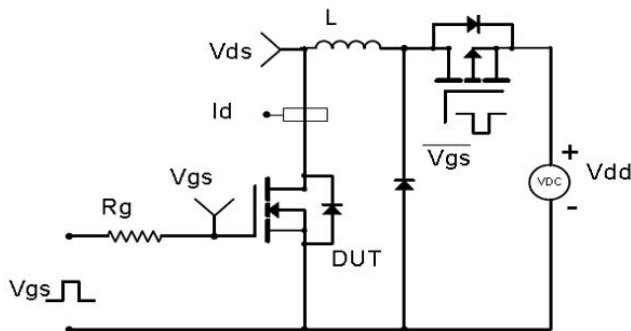
Gate Charge Test Circuit & Waveform



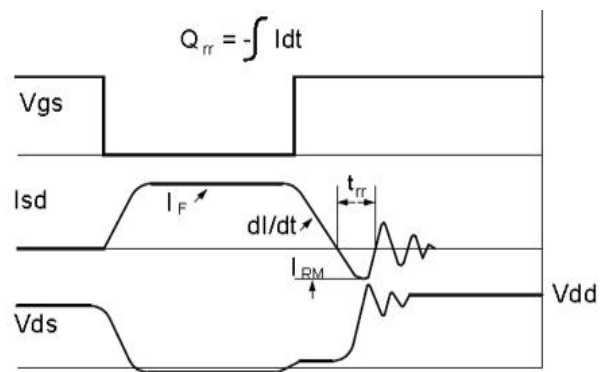
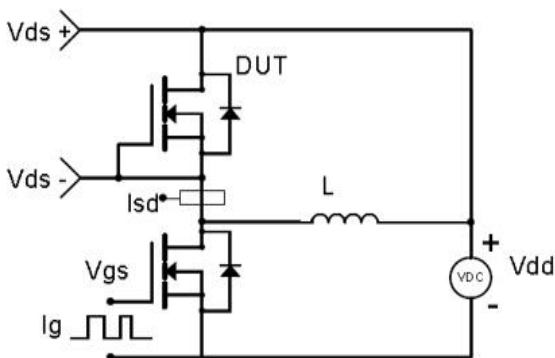
MOSFET Switching Test Circuit & Waveform



E_{AS} Test Circuit & Waveform

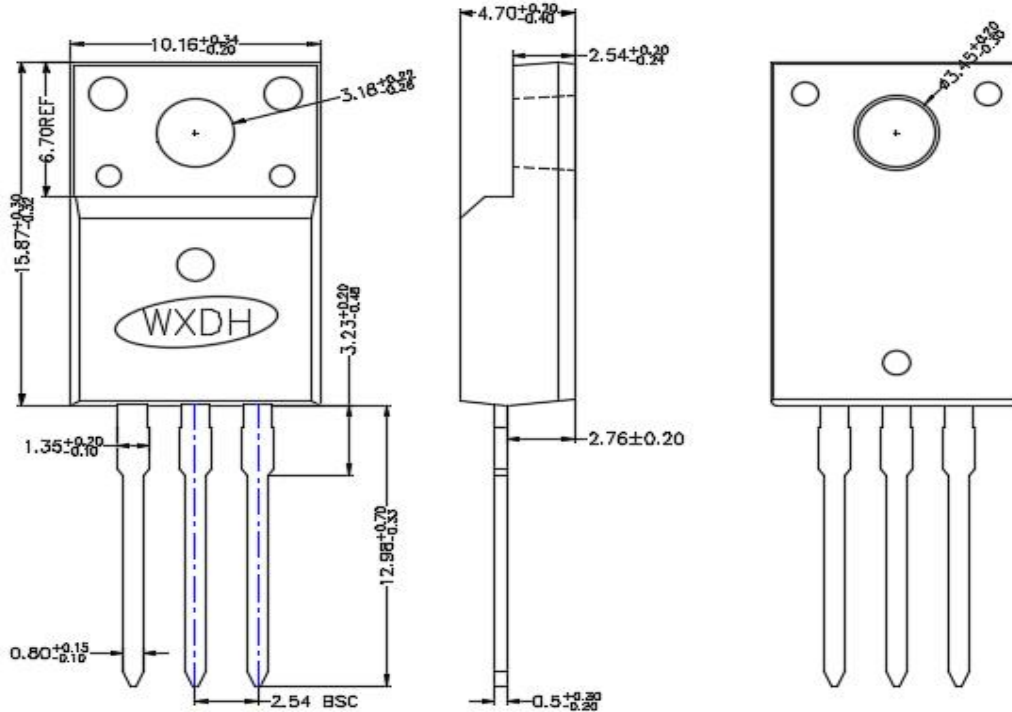


Diode Recovery Test Circuit & Waveform



Package Outline : TO-220F

*Dimensions in mm



Revision History

| Revision | Date | Major changes |
|----------|-----------|---------------------------|
| 1.0 | 2023/7/12 | Release of formal version |

Disclaimer

Unless otherwise specified in the datasheet, the product is designed and qualified as a standard commercial product and is not intended for use in applications that require extraordinary levels of quality and reliability, such as aviation, aerospace, life-support devices or systems.

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